

Search Notes

Application/Control No.

10/661,746

Examiner

Eric B. Chen

Applicant(s)/Patent under
Reexamination

HSIEH, CHIA-TA

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Performed inventor search for double patenting (PALM, eDAN)	7/18/2005	EC
EAST (all databases) - see search history printout	7/19/2005	EC
257/314-316; 438/266,585-587,706, 710,719,723,724,735,745,756,770 (text search only - see search history) (consulted K. Chen)	7/19/2005	EC